| CERTIFICATE OF MAILING BY FIRST CLASS MAIL (37 CFR 1.8) | | | Docket No. |
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| SEP 1 6 2005 | ION FOR ANTIREFLECTIVE C | COATING AND METHOD FOR | FORMING SAME |
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(22)Date of filing: 13.09.1985 (72)Inventor: TANAKA TOSHIHIKO

SHIRAISHI HIROSHI

HASEGAWA NOBUO

HAYASHIDA TETSUYA

(54) PATTERN FORMING METHOD

(57) Abstract:

PURPOSE: To form an ultrafine and accurate pattern and a pattern having high alignment accuracy by forming a film made of polysaccharide on a resist before exposing.

CONSTITUTION: Polysaccharide is formed on a photoresist film or an X-ray resist film. The polysaccharide is transparent, and has smaller refractive index than that of the resist. Therefore, it serves as a resist reflection preventive film. Since dimensional accuracy and alignment accuracy can be improved, a circuit can be integrated, a chip area can be contracted, and a high quality element having stable electric characteristic can be obtained at a high yield.

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